

Supporting information online

Table 5

Peak intensities of the specific simulations of the ^{29}Si MAS NMR spectra

Specimens	9544	176	116	FB4	K-ASGS	1406	AGM		K-EU2
							sim1	sim2	
T ₁ O (0Si, 4Al)	0.00	0.06	0.11	0.12	0.12	0.10	0.25	-	0.23
T ₁ O (1Si, 3Al)	0.00	0.44	0.92	0.99	1.36	1.04	1.98	-	1.95
T ₁ O (2Si, 2Al)	0.00	1.20	2.52	2.78	4.35	3.75	5.94	-	5.98
T ₁ O (3Si, 1Al)	0.00	1.39	2.75	3.33	3.40	5.63	7.92	20.00	7.97
T ₁ O (4Si, 0Al)	0.00	0.58	1.03	1.45	0.77	2.81	3.96	-	3.89
T ₁ m (0Si, 4Al)	0.00	0.00	0.01	0.03	0.01	0.11	0.21	-	0.27
T ₁ m (1Si, 3Al)	0.00	0.12	0.45	0.71	0.55	1.70	2.09	-	2.49
T ₁ m (2Si, 2Al)	0.00	3.13	5.46	6.32	6.44	8.32	7.51	-	8.26
T ₁ m (3Si, 1Al)	33.33	26.71	21.35	19.47	18.77	14.51	11.27	26.66	11.62
T ₁ m (4Si, 0Al)	0.00	2.38	4.40	4.81	5.91	5.38	5.63	-	5.72
T ₂ O (0Si, 4Al)	0.00	0.00	0.01	0.01	0.01	0.04	0.21	-	0.14
T ₂ O (1Si, 3Al)	0.00	0.12	0.37	0.46	0.55	0.83	2.09	-	1.66
T ₂ O (2Si, 2Al)	0.00	3.13	5.11	5.36	6.43	5.95	7.31	-	6.63
T ₂ O (3Si, 1Al)	33.33	26.71	21.62	20.13	18.77	15.32	11.27	26.66	11.00
T ₂ O (4Si, 0Al)	0.00	2.38	4.22	4.35	5.91	4.47	5.64	-	5.48
T ₂ m (0Si, 4Al)	0.00	0.03	0.09	0.14	0.08	0.33	0.42	-	0.39
T ₂ m (1Si, 3Al)	0.00	1.70	2.67	3.23	2.42	4.12	3.34	-	3.34
T ₂ m (2Si, 2Al)	33.33	26.30	20.81	18.49	18.63	13.09	9.18	26.66	9.23
T ₂ m (3Si, 1Al)	0.00	3.52	5.71	7.10	5.18	10.17	10.02	-	10.01
T ₂ m (4Si, 0Al)	0.00	0.12	0.40	0.71	0.37	2.31	3.76	-	3.73

Peak intensities in % are calculated assuming a constant Si/Al ratio of 3.0 and Loewenstein's Al-O-Al avoidance rule, after Xiao et al. (1995). The chemical shifts produced by replacement of Si by Al, to calculate different possible Si Q⁴ (nAl) n = 0, 1, 2, 3, 4, was assumed ± 4.85 ppm in all cases. The δ_x values are in ppm.

Table 6. Simulation of the ^{29}Si NMR spectra of the order-disorder models

Alternative models	<i>Two-step Orthoclase</i> Fig. 2c	<i>One-step Orthoclase</i> Fig. 2d	<i>Triclinic High sanidine</i> Fig. 4c	<i>Monoclinic High sanidine</i> Fig. 4d
Linewidth	1.10	1.10	1.35	1.35
t ₁ O	0.40	0.70	0.25	
t ₁ m	0.40	0.10	0.25	
t ₂ O	0.10	0.10	0.25	
t ₂ m	0.10	0.10	0.25	0.25
δT_{1O} (3Si, 1Al)	-100.8	-101.7	-101.7	-100.6
δT_{1m} (3Si, 1Al)	-100.8	-100.8	-100.6	-100.6
δT_{2O} (3Si, 1Al)	-96.5	-97.8	-97.8	-97.8
δT_{2m} (2Si, 2Al)	-91.7	-94.7	-94.7	-93.0
T ₁ O (0Si, 4Al)	0.06	0.12	0.31	
T ₁ O (1Si, 3Al)	0.97	0.99	2.47	
T ₁ O (2Si, 2Al)	5.15	2.96	7.41	
T ₁ O (3Si, 1Al)	10.14	3.95	9.88	
T ₁ O (4Si, 0Al)	3.90	1.98	4.94	
T ₁ m (0Si, 4Al)	0.06	0.03	0.31	
T ₁ m (1Si, 3Al)	0.97	0.78	2.47	
T ₁ m (2Si, 2Al)	5.15	6.37	7.41	
T ₁ m (3Si, 1Al)	10.14	18.15	9.88	
T ₁ m (4Si, 0Al)	3.90	4.68	4.94	
T ₂ O (0Si, 4Al)	0.30	0.03	0.31	
T ₂ O (1Si, 3Al)	3.48	0.78	2.47	
T ₂ O (2Si, 2Al)	9.15	6.31	7.41	
T ₂ O (3Si, 1Al)	11.67	18.15	9.88	
T ₂ O (4Si, 0Al)	4.62	4.68	4.94	
T ₂ m (0Si, 4Al)	0.30	0.22	0.31	
T ₂ m (1Si, 3Al)	3.48	3.71	2.47	
T ₂ m (2Si, 2Al)	10.26	16.42	7.41	
T ₂ m (3Si, 1Al)	11.67	8.49	9.88	
T ₂ m (4Si, 0Al)	4.62	1.17	4.94	

The letter “t” lowercase is used for the Al content in the tetrahedral sites, which are named with “T” uppercase. Peak intensities in % are calculated assuming a constant Si/Al ratio of 3.0 and Loewenstein’s Al-O-Al avoidance rule, after Xiao et al. (1995). The chemical shifts produced by replacement of Si by Al, to calculate different possible Si Q⁴ (nAl) n = 0, 1, 2, 3, 4, was of ± 4.85 ppm in all cases. The δ_x values are in ppm.